Product data sheet

1. General description

Planar passivated Silicon Controlled Rectifier (SCR) with sensitive gate in a SOT89 surface mountable plastic package. This SCR is designed to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

2. Features and benefits

- Sensitive gate
- High voltage capability
- · Planar passivated for voltage ruggedness and reliability
- Surface mountable package

3. Applications

- Ground Fault Circuit Interrupters (GFCI)
- General purpose switching and phase control
- Ignition circuits, CDI for 2- and 3-wheelers
- Motor control-e.g. small kitchen appliances

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Values	Unit
Absolute m	naximum rating			,
V_{RRM}	repetitive peak reverse voltage		600	V
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{sp} \le 109 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3	0.8	А
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25$ °C; $t_p = 10$ ms; Fig. 4; Fig. 5	8	А
		half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 8.3 \text{ ms}$	9	А
T _j	junction temperature		125	°C

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Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static cha	Static characteristics						
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$		15	-	100	μA
I _H	holding current	$V_D = 12 \text{ V}; T_J = 25 \text{ °C}; R_{GK(ext)} = 1 \text{ k}\Omega;$ Fig. 9		-	-	5	mA
V _T	on-state voltage	I _T = 1.6 A; T _j = 25 °C; <u>Fig. 10</u>		-	1.4	1.7	V
Dynamic	Dynamic characteristics						
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 600 V; T_j = 125 °C; R_{GK} = 1 k Ω ; exponential waveform		100	-	-	V/µs

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	
2	Α	anode		A - K
3	K	cathode		G sym037
mb	mb	mounting base; connected to anode	1 2 3	

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
NCR100Q-6M	SOT89	NCR100Q-6MJ	Reel	1000	SOT89L	8-Mar-2019

7. Marking

Table 4. Marking codes

Type number	Marking codes
NCR100Q-6M	NCR1006M

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
V_{DRM}	repetitive peak off-state voltage		600	V
V_{RRM}	repetitive peak reverse voltage		600	V
I _{T(AV)}	average on-state current	half sine wave; T _{sp} ≤ 109 °C	0.51	А
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{sp} \le 109 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3	0.8	А
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 10 \text{ ms}$; Fig. 4; Fig. 5	8	А
		half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 8.3 \text{ ms}$	9	А
l ² t	I ² t for fusing	t _p = 10ms; sine wave	0.32	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 0.2 mA	50	A/µs
I _{GM}	peak gate current		1	А
V_{GM}	peak gate voltage		5	V
P_{GM}	peak gate power		2	W
$P_{G(AV)}$	average gate power	over any 20 ms period	0.1	W
T _{stg}	storage temperature		-40 to 150	°C
T _j	junction temperature		125	°C

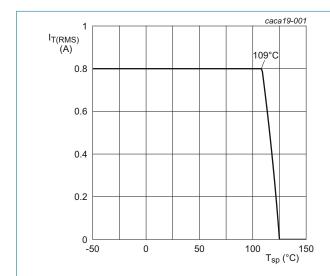
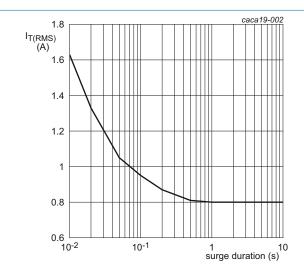
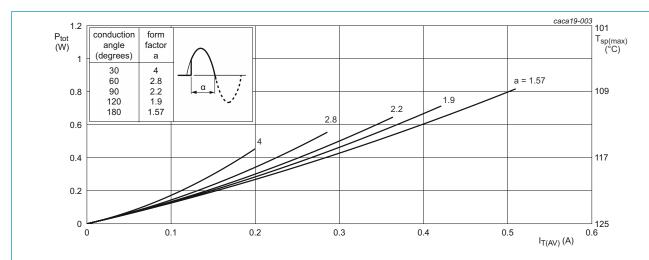


Fig. 1. RMS on-state current as a function of solder point temperature; maximum values



 $f = 50Hz; T_{sp} = 109 \, ^{\circ}C$

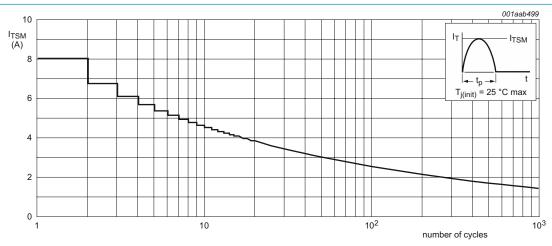
Fig. 2. RMS on-state current as a function of surge duration; maximum values



 α = conduction angle

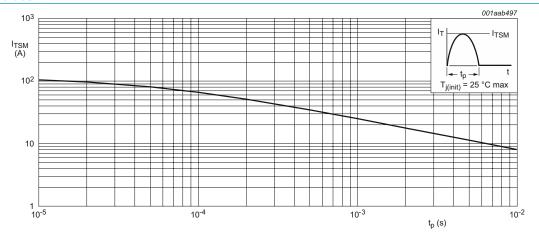
a = form factor = $I_{T(RMS)}$ / $I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



t_p ≤ 10 ms

Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-sp)}}$	thermal resistance from junction to solder point	Fig. 6	-	-	20	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient free air	in free air	-	90	-	K/W

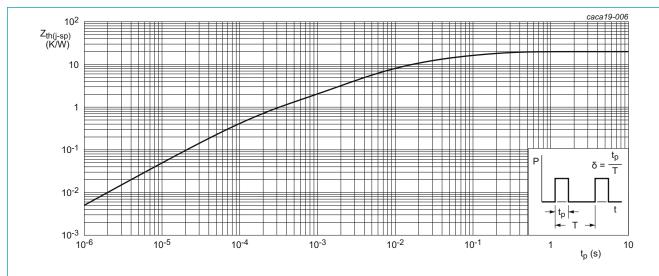


Fig. 6. Transient thermal impedance from junction to solder point as a function of pulse duration

10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$	15	-	100	μA
IL	latching current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ $R_{GK(ext)} = 1 \text{ k}\Omega; Fig. 8$	-	-	6	mA
I _H	holding current	$V_D = 12 \text{ V}; T_j = 25 \text{ °C};$ $R_{GK(ext)} = 1 \text{ k}\Omega; Fig. 9$	-	-	5	mA
V _T	on-state voltage	I _T = 1.6 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.4	1.7	V
V_{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11	-	0.7	1	V
		$V_D = 600 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 ^{\circ}\text{C}$	0.2	0.5	-	V
I _D	off-state current	V _D = 600 V; T _j = 125 °C	-	-	0.1	mA
I _R	reverse current	V _D = 600 V; T _j = 125 °C	-	-	0.1	mA
Dynamic o	characteristics			·		
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 600 V; T_{j} = 125 °C; R_{GK} = 1 k Ω ; exponential waveform	100	-	-	V/µs
t _{gt}	gate-controlled turn-on time	$I_{TM} = 2 \text{ A}; V_D = 600 \text{ V}; I_G = 1 \text{ mA};$ $(dI_G/dt)_M = 0.1 \text{ A/}\mu\text{s}; T_j = 25 \text{ °C}$	-	2	-	μs
t _q	commutated turn-off time	$\begin{split} &V_{\text{DM}} = 402 \text{ V; } T_{j} = 125 \text{ °C; } I_{\text{TM}} = 1.6 \text{ A;} \\ &V_{\text{R}} = 35 \text{ V; } dV_{\text{D}}/dt = 2 \text{ V/\mus; } (dI_{\text{T}}/dt)_{\text{M}} = \\ &30 \text{ A/\mus; } R_{\text{GK(ext)}} = 1 \text{ k}\Omega \text{ ; } (V_{\text{DM}} = 67\% \text{ of } V_{\text{DRM}}) \end{split}$	-	100	-	μs

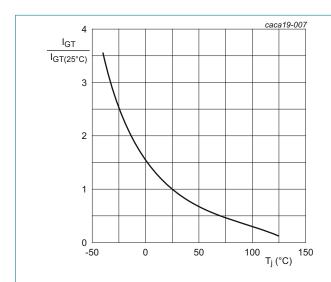


Fig. 7. Normalized gate trigger current as a function of junction temperature

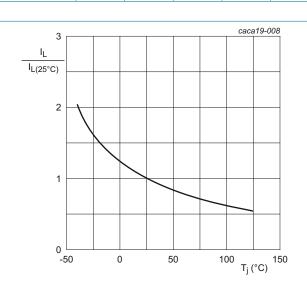


Fig. 8. Normalized latching current as a function of junction temperature

SCR

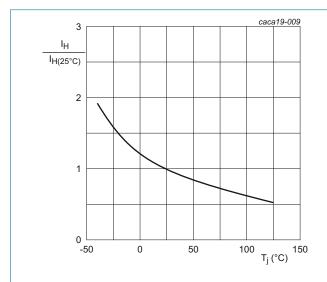
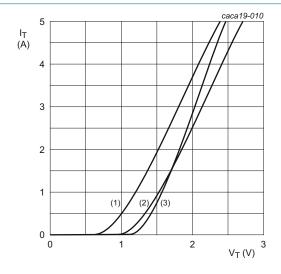


Fig. 9. Normalized holding current as a function of junction temperature



 V_o = 1.173 V; R_s = 0.3437 Ω

(1) T_i = 125 °C; typical values

(2) T_j = 125 °C; maximum values (3) T_j = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

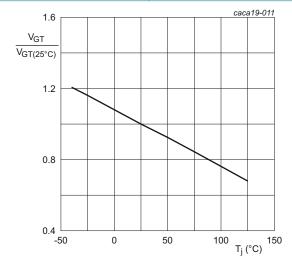
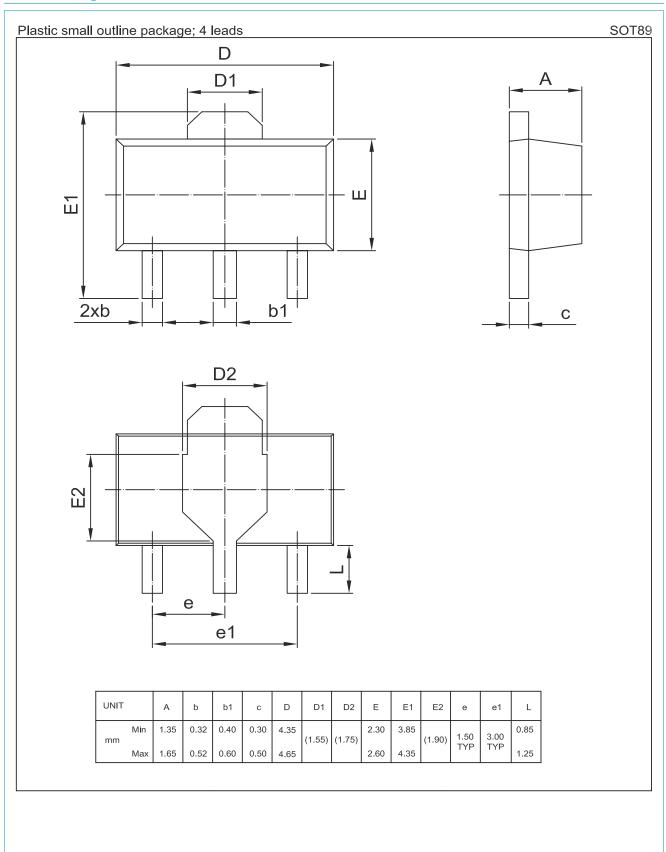


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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